

## Publications

Written by Administrator

Thursday, 06 September 2012 08:16 - Last Updated Wednesday, 25 February 2015 11:27

---

### Conference papers

1. I. Ciornel, M. Asprou, and E. Kyriakides, "A real time innovative scheme for power losses calculation," *PowerAfrica '12, PES Conference and Exposition in Africa 2012*, Johannesburg, South Africa, Jul. 2012.
2. M. Asprou, E. Kyriakides and M. Albu, "The effect of parameters and measurement uncertainties on hybrid state estimation," *IEEE PES General Meeting*, San Diego, CA, USA, Jul. 2012.
3. Y. Yiasoumi, I. Ciornel, M. Asprou, and E. Kyriakides, "Impact of loss calculation on different loss allocation procedures," *IEEE PowerTech 2013*, Grenoble, France, pp.1-5 Jun. 2013.
4. Y. Tofis, L. Hadjidemetriou, and E. Kyriakides, "An intelligent load shedding mechanism for maintaining frequency stability," *IEEE PowerTech 2013*, Grenoble, France, pp.1-5, Jun. 2013.
5. M. Asprou, Y. Yiasemi, E. Kyriakides, Y. Ioannou, A. Petousis, M. Michael, and S. Stavrinos Application of synchronized measurement technology in the Cyprus power transmission system, *2nd International Energy Conference on Power Options for the Eastern Mediterranean Region*, Nicosia, Cyprus, pp. 1-6, Oct. 2013.
6. Y. Tofis, Y. Yiasemi, E. Kyriakides, and K. Kansala, "Adaptive Frequency Control Application for a Real Autonomous Islanded Grid," *IEEE PES General Meeting 2014*, Washington DC, USA, Jul. 2014.

### Journal papers

1. Y. Yiasoumi, I. Ciornel, M. Asprou, and E. Kyriakides, "Near real time loss allocation in transmission networks," *IEEE Transactions on Smart Grids*, pp. 1-8. (under review).

## Publications

Written by Administrator

Thursday, 06 September 2012 08:16 - Last Updated Wednesday, 25 February 2015 11:27

2. Y. Tofis, and E. Kyriakides, "A Plug and Play Selective Load Shedding Scheme for Power Systems," *IEEE Systems Journal*, pp. 1-8. (under review)
  
  3. P. Demetriou, M. Asprou, J. Q. Tortos, and E. Kyriakides, "Dynamic IEEE Test Systems for Transient Stability Analysis," *IEEE Systems Journal*, pp. 1-8 (under review).